

FEATURES

- LIN 2.x/ISO 17987-4:2016 (12V)/SAE J2602 compliant;
- AEC-Q100 qualified;
- Thermally protected;
- Transmit data (TXD) dominant time-out function;
- Bus terminal current limit protected;
- Under voltage on battery;
- Very low current consumption in Sleep mode;
- Support local and remote wake-up;
- Enable an external high voltage regulator by INH;
- Baud rates up to 20kbps;
- Very low ElectroMagnetic Emission (EME);
- High ElectroMagnetic Immunity (EMI);
- Available in SOP8 and DFN3*3-8 packages. DFN3*3-8 with improved Automated Optical Inspection (AOI) capability.

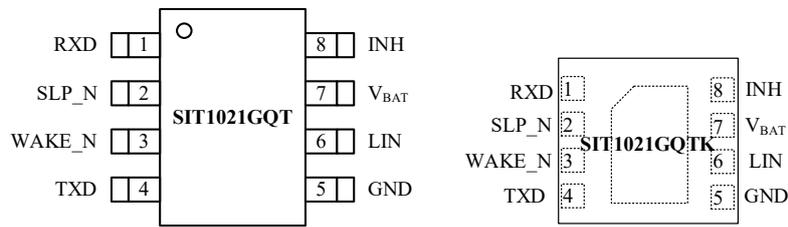
DESCRIPTION

The SIT1021GQ is a physical layer transceiver of Local Interconnect Network (LIN). It is compliant with LIN 2.0/LIN 2.1/LIN 2.2/LIN 2.2A/ISO 17987-4:2016 (12V) and SAE J2602 standards. It is typically used for low speed in-vehicle networks using baud rates from 1 kbps to 20 kbps. The LIN protocol data stream at the transmit data input (TXD) is converted by the SIT1021GQ into a bus signal with optimized wave shaping to minimize ElectroMagnetic Emission (EME).

The SIT1021GQ converts the data stream on LIN bus to logic level signals that are sent to the microprocessor via the pin RXD. The LIN bus is pulled high by the internal slave resistor. Master applications require an external pull-up resistor in series with a diode to connect pin V_{BAT} and pin LIN.

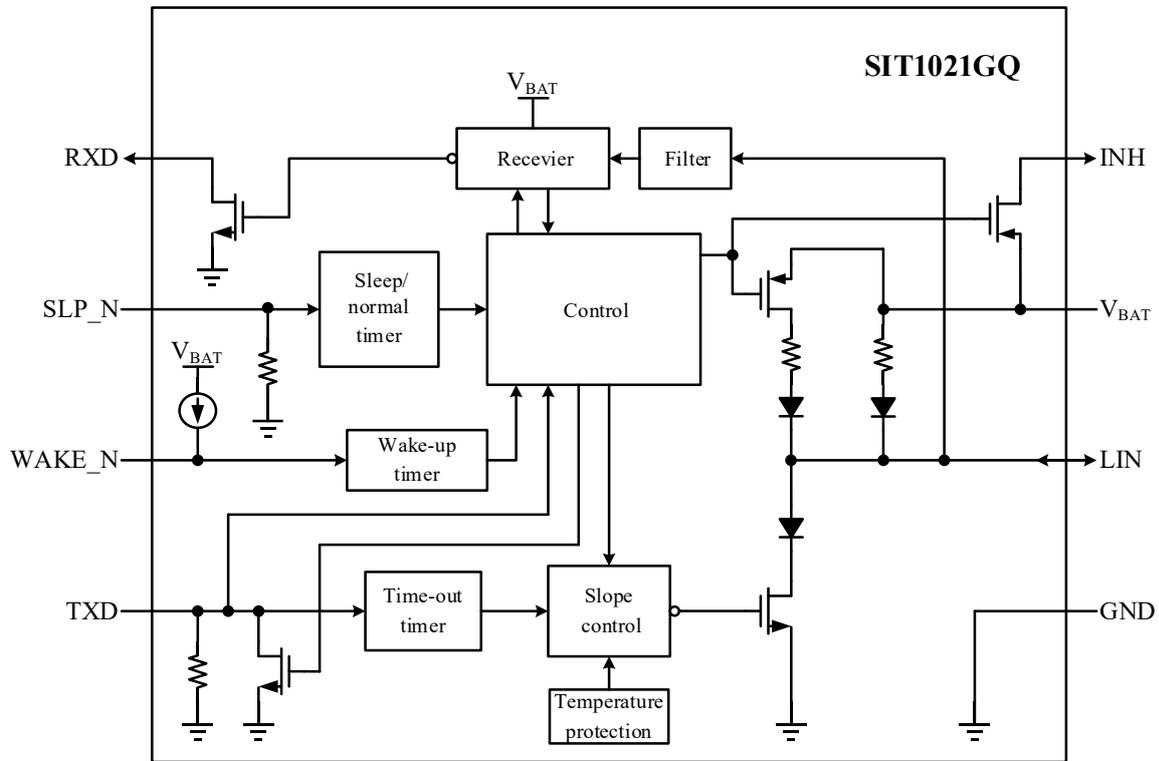
The SIT1021GQ operates within a voltage range of 5.5V~27V and supports 12V applications. In sleep mode, it achieves extremely low current consumption. Upon fault occurrence, it rapidly reduces power consumption to the minimum level. The device can be transitioned into normal operating mode via messages on the LIN pin, WAKE_N pin, or SLP_N pin. Additionally, the SIT1021GQ can selectively enable various external power modules on the node through the INH output pin, thereby reducing battery consumption at the entire application system level.

The power consumption is reduced to a minimum if in failure modes. It also provides a high voltage output pin INH to enable an external high voltage regulator which is used to support the microprocessor.

PIN CONFIGURATION

Fig 1 SIT1021GQ pin configuration diagrams
PIN DESCRIPTION
Table 1 Pin description

Pin	Symbol	Description
1	RXD	receive data output (open-drain); active LOW after a wake-up event
2	SLP_N	sleep control input (active LOW); controls inhibit output; resets wake-up source flag on TXD and wake-up request on RXD
3	WAKE_N	local wake-up input (active LOW); negative edge triggered
4	TXD	transmit data input; active LOW output after a local wake-up event
5	GND	ground
6	LIN	LIN bus line input/output
7	V _{BAT}	battery supply voltage
8	INH	battery related inhibit output for controlling an external voltage regulator; active HIGH after a wake-up event

Note: The metal pad on the back of the DFN3*3-8 package is recommended to be grounded.

BLOCK DIAGRAM

Fig 2 Block diagram

FEATURE DESCRIPTION**1 Overview**

SIT1021GQ is an interface device used between the LIN protocol controller and the physical bus. It can be used for in-vehicle and industrial control with a data rate up to 20kbps. SIT1021GQ receives the data stream sent by protocol controller at the pin TXD, and converts it into a bus signal with appropriate slew rate and waveform shaping. The input data on LIN bus is output to external microcontroller by pin RXD. This device is compliant with LIN 2.0/LIN 2.1/LIN 2.2/LIN 2.2A/ISO 17987-4:2016 (12V) and SAE J2602 standards.

2 Short-circuit protection

Pin TXD provides an internal pull-down to GND to apply a predefined level on TXD when it is not enabled. The pin SLP_N also provides an internal pull-down to force the transceiver to enter sleep mode when SLP_N is not enabled.

Pin RXD will be left floating and limit the output current of transmitter to prevent a short-circuit between LIN and VBAT or GND if the supply on pin VBAT is turned off. There is no reverse current at the bus terminal, and the connection between LIN supply can be shut off without affecting the bus.

3 Thermal Shutdown

In normal mode, the over-temperature protection circuit will disable the output driver when the junction temperature of SIT1021GQ exceeds the shutdown junction temperature $T_{j(sd)}$. The driver is enabled again when the junction temperature has dropped below $T_{j(sd)}$. If V_{BAT} falls below $V_{th(VBATL)L}$, the protection circuit disables the output driver; when V_{BAT} exceeds $V_{th(VBATL)H}$, the driver is enabled again.

4 TXD dominant time-out function

A TXD dominant time-out timer circuit prevents the bus lines from being driven to a permanent dominant state (blocking all network communication) if pin TXD is forced permanently LOW by a hardware and/or software application failure. The timer is triggered by a negative edge on pin TXD. If the duration of the LOW level on pin TXD exceeds the internal timer value ($t_{to(dom)TXD}$), the transmitter is disabled, driving the bus lines into a recessive state. The timer is reset by a positive edge on pin TXD.

5 Operating modes

As shown in Fig 3, the SIT1021GQ supports four functional modes for Sleep mode, Standby mode, normal mode and Power-on mode. The operating states in each mode are shown in Table 2

Sleep mode: This mode is the lowest power consumption mode of the SIT1021GQ. It can be woken up remotely via pin LIN, or woken up locally via pin WAKE_N, or activated directly via pin SLP_N. The pin WAKE_N, pin SLP_N and pin LIN are filtered to prevent accidental wake up events. The wake-up events

for SIT1021GQ in sleep mode is: the remote wake up time via pin LIN must be longer than $t_{\text{wake}(\text{dom})\text{LIN}}$; the local wake up time via pin WAKE_N must be longer than $t_{\text{wake}(\text{dom})\text{WAKE_N}}$; the time wake up directly via pin SLP_N must be longer than t_{gotonorm} .

Sleep mode is only entered when the pin SLP_N is low and from normal mode. To enter Sleep mode successfully (INH becomes floating), the sleep command (SLP_N = 0) must be maintained for at least $t_{\text{gotosleep}}$. The pin INH is only floating in sleep mode and going into high in others modes.

Standby mode: It is entered whenever a local or remote wake-up occurs while the device is in Sleep mode. Standby mode is signaled through a low level on pin RXD. The pin INH will be set high and activate the external voltage regulator and the microcontroller after the device enters standby mode from sleep mode.

Setting pin SLP_N high during Standby mode results in the following events:

- (1) An immediate reset of the wake-up source flag; thus releasing the possible strong pull-down at pin TXD before the actual mode change (after t_{gotonorm}) is performed.
- (2) A change into Normal mode if the high level on pin SLP_N has been maintained for a certain time period (t_{gotonorm}).
- (3) An immediate reset of the wake-up request signal on pin RXD.

Normal mode: Only in Normal mode the receiver and transmitter are active and the SIT1021GQ is able to transmit and receive data via the LIN bus. The high level of bus represents recessive and low level represents dominant. The receiver detects the data stream on the LIN bus and outputs it to the microcontroller via pin RXD. Normal mode is entered as a high level on pin SLP_N and maintained for a time of at least t_{gotonorm} while the SIT1021GQ is in Sleep, Power-up or Standby mode. The Sleep mode is entered by setting pin SLP_N low for longer than $t_{\text{gotosleep}}$.

Power-on mode: When SIT1021GQ is in Power-on mode: pin RXD is left floating, pin TXD is weakly pulled down, transmitter and receiver are not activated. If the high-level duration of the SLP_N pin exceeds t_{gotonorm} , the device enters normal mode.

6 Wake-up source recognition

In Sleep mode, SIT1021GQ can be woken up remotely via the LIN bus or be woken up locally via the pin WAKE_N. The wake-up source flag can be read by detecting the state of pin TXD in the Standby mode. If an external pull-up resistor on pin TXD to the power supply voltage of the microcontroller has been added, a high level indicates a remote wake-up request (weak pull-down at pin TXD) and a LOW level indicates a local wake-up request (strong pull-down at pin TXD; much stronger than the external pull-up resistor). The wake-up request flag (signaled on pin RXD) as well as the wake-up source flag (signaled on pin TXD) are reset immediately after the microcontroller sets pin SLP_N high.

7 Wake Up Events

In sleep mode, the device can be woken up by the following three ways:

- (1) Remote wake-up via pin LIN;
- (2) Local wake-up via pin WAKE_N;
- (3) Wake up directly via pin SLP_N.

8 Remote and local wake-up

Remote wake-up on the pin LIN: When a falling edge at pin LIN followed by a low level maintained longer than $t_{wake(dom)LIN}$ and a rising edge at pin LIN respectively, the process is regarded as a valid remote wake-up event (see Fig 4).

Local wake-up on the pin WAKE_N: When A falling edge at pin LIN followed by a low level maintained longer than $t_{wake(dom)WAKE_N}$, the process is regarded as a valid remote wake-up event. The pin WAKE_N provides an internal pull-up path to VBAT. To prevent EMI issues, it is recommended to connect the unused pin WAKE_N to VBAT.

When a local or remote wake-up occurs, pin INH is activated (turns to high) and the internal slave termination resistor is turned on. The wake-up request is indicated by a low active wake-up request signal on pin RXD to interrupt the microcontroller.

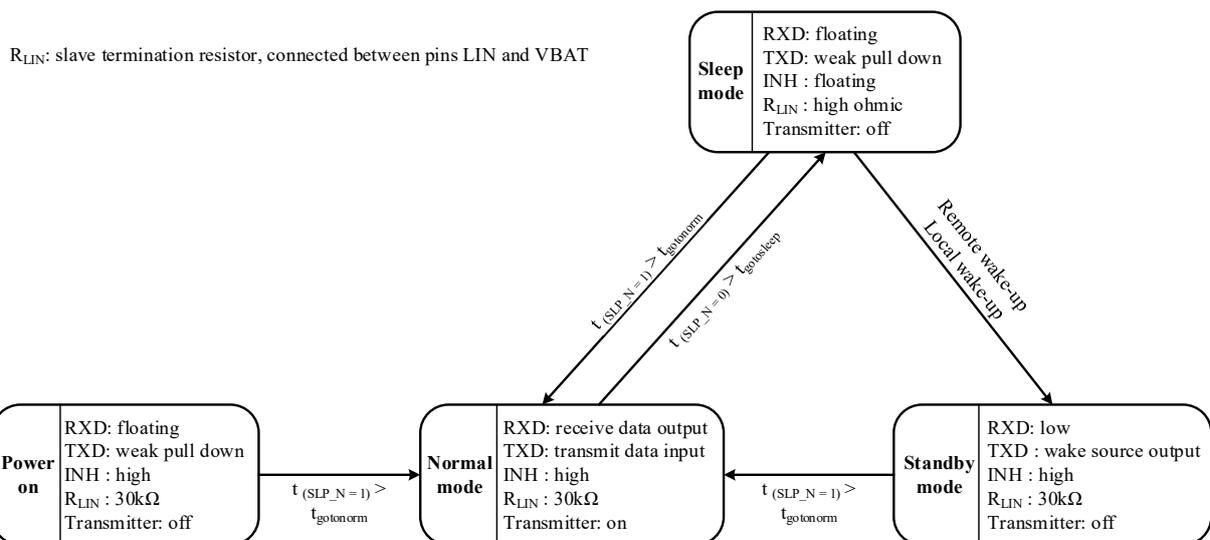
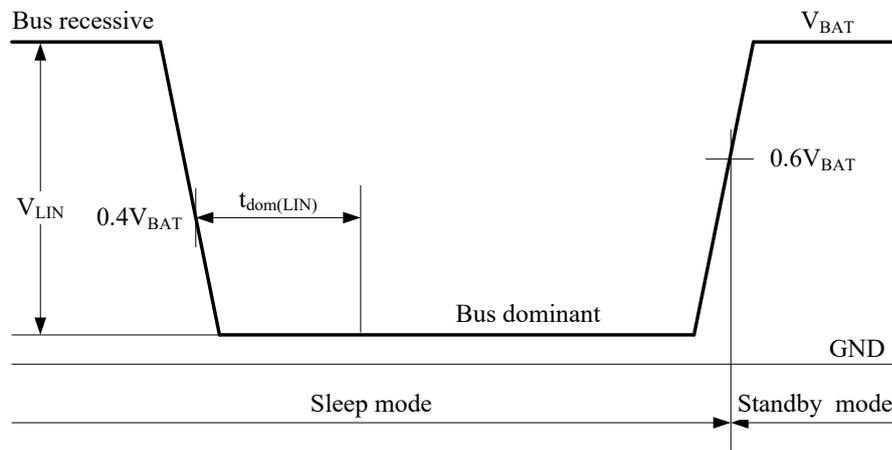


Fig 3 State diagram

Table 2 Operating modes

Mode	SLP_N	TXD	RXD	INH	Transmitter	Remarks
Sleep	low	weak pull-down	floating	floating	off	no wake-up request detected
Standby	low	weak pull-down if remote wake-up; strong pull-down if local wake-up	low	high	off	wake-up request detected; in this mode the microcontroller can read the wake-up source: remote or local wake-up
Normal	high	recessive: high dominant: low	recessive: high dominant: low	high	on	
Power-on	low	weak pull-down	floating	high	off	


Fig 4 Remote wake-up behavior

LIMITING VALUES

Parameter	Symbol	Conditions	Range	Unit
battery supply voltage	V_{BAT}	with respect to GND	-0.3 ~ +42	V
voltage on pin TXD	V_{TXD}	ISLP_N no limitation	-0.3 ~ +6	V
		ISLP_N < 500 μ A	-0.3 ~ +7	
voltage on pin RXD	V_{RXD}	ISLP_N no limitation	-0.3 ~ +6	V
		ISLP_N < 500 μ A	-0.3 ~ +7	
voltage on pin SLP_N	V_{SLP_N}	ISLP_N no limitation	-0.3 ~ +6	V
		ISLP_N < 500 μ A	-0.3 ~ +7	
voltage on pin LIN	V_{LIN}	with respect to GND	-42 ~ +42	V
voltage on pin WAKE_N	V_{WAKE_N}		-0.3 ~ +42	V
voltage on pin INH	V_{INH}		-0.3 ~ $V_{BAT}+0.3$	V
virtual junction temperature	T_j		-40 ~ 150	$^{\circ}$ C
storage temperature	T_{stg}		-55 ~ 150	$^{\circ}$ C
ambient temperature	T_{amb}		-40 ~ 125	$^{\circ}$ C

The maximum limit parameters mean that exceeding these values may cause irreversible damage to the device. Under these conditions, it is not conducive to the normal operation of the device. The continuous operation of the device at the maximum allowable rating may affect the reliability of the device. The reference point for all voltages is ground.

THERMAL INFORMATION

Parameter	Symbol	Conditions	Value	Unit
$R_{\theta JA}$	Junction-to-ambient thermal resistance	SOP8	95	$^{\circ}$ C/W
		DFN3*3-8	65	$^{\circ}$ C/W
$R_{\theta JC}$	Junction-to-case thermal resistance	SOP8	46	$^{\circ}$ C/W
		DFN3*3-8	35	$^{\circ}$ C/W

STATIC CHARACTERISTICS

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Supply						
battery supply current	IBAT	Sleep mode; bus recessive; (V _{BAT} =5.5V~18V; V _{LIN} =V _{BAT} ; V _{WAKE_N} =V _{BAT} ; V _{TXD} =0V; V _{SLP_N} =0V)	2	8	30	μA
		Standby mode; bus recessive; (V _{INH} =V _{BAT} ; V _{LIN} =V _{BAT} ; V _{WAKE_N} =V _{BAT} ; V _{TXD} =0V; V _{SLP_N} =0V)	100	220	500	μA
		Standby mode; bus dominant; (V _{BAT} =12V; V _{INH} =12V; V _{LIN} =0V; V _{WAKE_N} =12V; V _{TXD} =0V; V _{SLP_N} =0V)	300	600	1000	μA
		Normal mode; bus recessive; (V _{INH} =V _{BAT} ; V _{LIN} =V _{BAT} ; V _{WAKE_N} =V _{BAT} ; V _{TXD} =5V; V _{SLP_N} =5V)	150	300	600	μA
		Normal mode; bus dominant; (V _{BAT} =12V; V _{INH} =12V; V _{WAKE_N} =12V; V _{TXD} =0V; V _{SLP_N} =5V)	0.5	1.2	3	mA
Power-on reset						
low-level V _{BAT} reset threshold voltage	V _{th(POR)L}		3	3.6	4.3	V
high-level V _{BAT} reset threshold voltage	V _{th(POR)H}		3.2	3.9	4.5	V
reset hysteresis voltage	V _{hys(POR)}		0.05	0.25	0.6	V
V _{BAT} power-down threshold voltage	V _{th(BAT)L}		3.9	4.2	4.7	V

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
V _{BAT} power-on threshold Voltage	V _{th(BAT)H}		4.2	4.5	4.9	V
V _{BAT} hysteresis voltage	V _{hys(BAT)}		0.05	0.3	0.6	V
Pin TXD						
high-level input voltage	V _{IH}		2		7	V
low-level input voltage	V _{IL}		-0.3		+0.8	V
hysteresis voltage	V _{hys} ^[1]		50	200	400	mV
pull-down resistance on pin TXD	R _{PD(TXD)}	V _{TXD} =5V	140	500	1200	kΩ
low-level input current	I _{IL}	V _{TXD} =0V	-5		+5	μA
low-level output current	I _{OL}	local wake-up request; Normal mode; V _{WAKE_N} =0V; V _{LIN} =V _{BAT} ; V _{TXD} =0.4V	1.5			mA
Pin SLP_N						
high-level input voltage	V _{IH}		2		7	V
low-level input voltage	V _{IL}		-0.3		0.8	V
hysteresis voltage	V _{hys} ^[1]		50	200	400	mV
pull-down resistance on pin SLP_N	R _{PD(SLP_N)}	V _{SLP_N} =5V	140	500	1200	kΩ
low-level input current	I _{IL}	V _{SLP_N} =0V	-5		5	μA
Pin RXD						
low-level output current	I _{OL}	Normal mode; V _{RXD} =0.4V; V _{LIN} =0V	1.5			mA
high-level leakage current	I _{LH}	Normal mode; V _{RXD} =5V; V _{LIN} =V _{BAT}	-5		5	μA
Pin WAKE_N						
high-level input voltage	V _{IH}		V _{BAT} -1		V _{BAT} +0.3	V
low-level input voltage	V _{IL}		-0.3		V _{BAT} -3.3	V
low-level pull-up current	I _{pu(L)}	V _{WAKE_N} =0V;	-30	-12	-1	μA
high-level leakage current	I _{LH}	V _{WAKE_N} =27V; V _{BAT} =27V	-5		5	μA
Pin INH						
switch-on resistance between pins V _{BAT} and INH	R _{SW}	Standby; Normal and Power-on mode; I _{INH} =-15mA; V _{BAT} =12V		20	50	Ω

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
high-level leakage current	I_{LH}	Sleep mode; $V_{INH}=27V$; $V_{BAT}=27V$	-5		5	μA
Pin LIN						
current limitation for driver dominant state	I_{BUS_LIM}	$V_{TXD}=0V$; $V_{LIN}=V_{BAT}=18V$	40		100	mA
pull-up resistance	R_{pu}	Sleep mode; $V_{SLP_N}=0V$	50		250	$k\Omega$
receiver recessive input leakage current	$I_{BUS_PAS_rec}$	$V_{TXD}=5V$; $V_{LIN}=27V$; $V_{BAT}=5.5V$			15	μA
receiver recessive input leakage current	$I_{BUS_PAS_dom}$	Normal mode; $V_{TXD}=5V$; $V_{LIN}=0V$; $V_{BAT}=12V$	-600			μA
loss-of-ground bus current	$I_{BUS_NO_GND}$	$V_{BAT}=27V$; $V_{LIN}=0V$	-1000		10	μA
loss-of-battery bus current	$I_{BUS_NO_BAT}$	$V_{BAT}=0V$; $V_{LIN}=27V$			10	μA
receiver dominant reverse threshold voltage	$V_{th(dom)RX}$				$0.4V_{BAT}$	V
receiver recessive reverse threshold voltage	$V_{th(rec)RX}$		$0.6V_{BAT}$			V
receiver center threshold voltage	$V_{th(RX)cntr}$	$V_{th(RX)cntr}=(V_{th(rec)RX}+$ $V_{th(dom)RX})/2$	$0.475V_{BAT}$	$0.5V_{BAT}$	$0.525V_{BAT}$	V
receiver hysteresis threshold voltage	$V_{th(hys)RX}$	$V_{th(hys)RX}=V_{th(rec)RX}-V_{th(dom)RX}$			$0.175V_{BAT}$	V
slave resistance	R_{slave}	Connected between pin LIN and V_{BAT} ; $V_{LIN}=0V$; $V_{BAT}=12V$; $V_{TXD}=V_{SLP_N}=5V$	20	30	60	$k\Omega$
capacitance on pin LIN	$C_{LIN}^{[1]}$				30	pF
dominant output voltage	$V_{o(dom)}$	Normal mode; $V_{TXD}=0V$; $V_{BAT}=7V$			1.4	V
		Normal mode; $V_{TXD}=0V$; $V_{BAT}=18V$			2.0	V
Thermal shutdown						
shutdown junction temperature	$T_{j(sd)}^{[1]}$		150	175	200	$^{\circ}C$

(Unless specified otherwise; $5.5V \leq V_{BAT} \leq 27V$, $-40^{\circ}C \leq T_j \leq 150^{\circ}C$; typical in $V_{BAT}=12V$, $T_{amb}=25^{\circ}C$.)

[1] Guaranteed by design; not tested in production.

DYNAMIC CHARACTERISTICS

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Duty cycles						
duty cycle 1	δ_1 ^{[1][2]}	$V_{th(rec)(max)}=0.744 \times V_{BAT}$; $V_{th(dom)(max)}=0.581 \times V_{BAT}$; $t_{bit}=50\mu s$; $V_{BAT}=7V \sim 18V$ Fig 5	0.396			
		$V_{th(rec)(max)}=0.76 \times V_{BAT}$; $V_{th(dom)(max)}=0.593 \times V_{BAT}$; $t_{bit}=50\mu s$; $V_{BAT}=5.5V \sim 7V$ Fig 5	0.396			
duty cycle 2	δ_2 ^{[2][3]}	$V_{th(rec)(min)}=0.422 \times V_{BAT}$; $V_{th(dom)(min)}=0.284 \times V_{BAT}$; $t_{bit}=50\mu s$; $V_{BAT}=7.6V \sim 18V$ Fig 5			0.581	
		$V_{th(rec)(min)}=0.41 \times V_{BAT}$; $V_{th(dom)(min)}=0.275 \times V_{BAT}$; $t_{bit}=50\mu s$; $V_{BAT}=6.1V \sim 7.6V$ Fig 5			0.581	
duty cycle 3	δ_3 ^{[1][2]}	$V_{th(rec)(max)}=0.778 \times V_{BAT}$; $V_{th(dom)(max)}=0.616 \times V_{BAT}$; $t_{bit}=96\mu s$; $V_{BAT}=7V \sim 18V$ Fig 5	0.417			
		$V_{th(rec)(max)}=0.797 \times V_{BAT}$; $V_{th(dom)(max)}=0.630 \times V_{BAT}$; $t_{bit}=96\mu s$; $V_{BAT}=5.5V \sim 7V$ Fig 5	0.417			
duty cycle 4	δ_4 ^{[2][3]}	$V_{th(rec)(min)}=0.389 \times V_{BAT}$; $V_{th(dom)(min)}=0.251 \times V_{BAT}$; $t_{bit}=96\mu s$; $V_{BAT}=7.6V \sim 18V$ Fig 5			0.590	
		$V_{th(rec)(min)}=0.378 \times V_{BAT}$; $V_{th(dom)(min)}=0.242 \times V_{BAT}$; $t_{bit}=96\mu s$; $V_{BAT}=6.1V \sim 7.6V$ Fig 5			0.590	
Timing characteristics						
receiver propagation delay	$t_{PD(RX)}$ ^[4]				6	μs
receiver propagation delay symmetry	$t_{PD(RX)sym}$ ^[4]		-2		2	μs

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
LIN dominant wake-up time (remote wake-up)	$t_{wake(dom)LIN}$	Sleep mode	30	80	150	μs
dominant wake-up time on pin WAKE_N (local wake-up)	$t_{wake(dom)WAKE_N}$	Sleep mode	7	30	50	μs
go to normal time	$t_{gotonorm}$		3	7	15	μs
go to sleep time	$t_{gotosleep}$		3	7	15	μs
TXD dominant time-out time	$t_{to(dom)TXD}$	$V_{TXD}=0V$	27	55	90	ms

(Unless specified otherwise; $5.5V \leq V_{BAT} \leq 27V$, $-40^\circ C \leq T_j \leq 150^\circ C$; typical in $V_{BAT}=12V$, $T_{amb}=25^\circ C$.)

$$[1] \delta 1, \delta 3 = \frac{t_{bus(rec)(min)}}{2 \times t_{bit}};$$

[2] Bus load conditions are: (1) $C_L=1nF$, $R_L=1k\Omega$; (2) $C_L=6.8nF$, $R_L=660\Omega$; (3) $C_L=10nF$, $R_L=500\Omega$;

$$[3] \delta 2, \delta 4 = \frac{t_{bus(rec)(max)}}{2 \times t_{bit}};$$

[4] Load condition on pin RXD: $C_{RXD}=20pF$, $R_{RXD}=2.4k\Omega$.

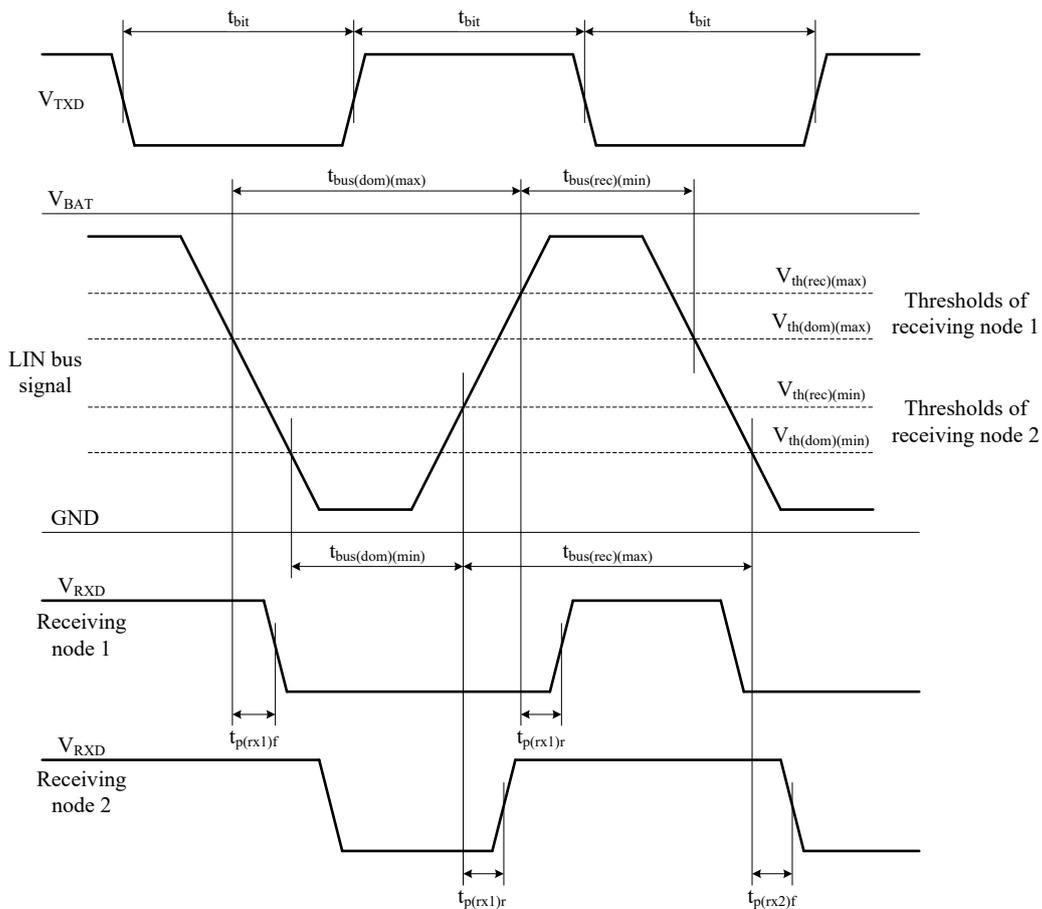
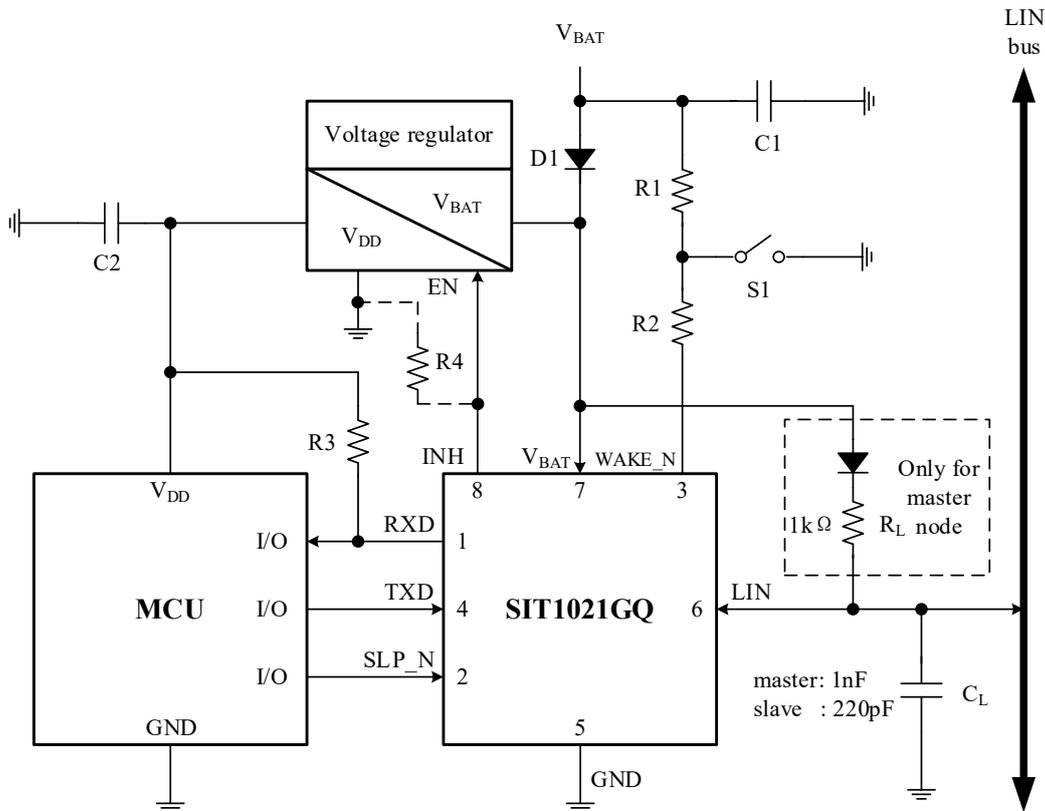
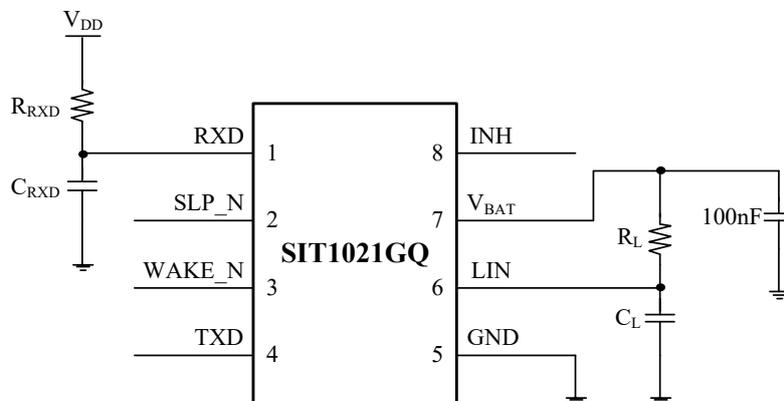


Fig 5 Timing diagram LIN transceiver

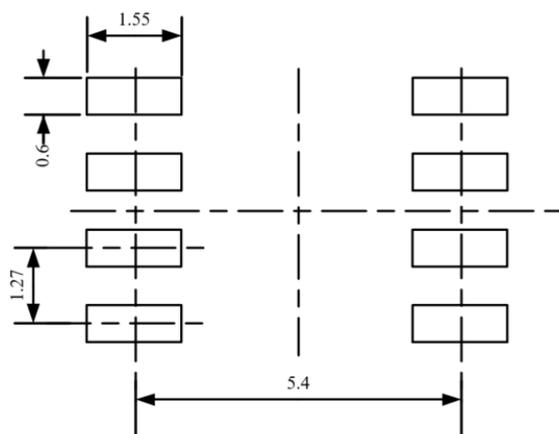
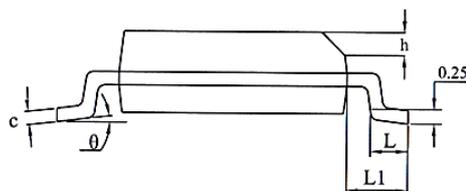
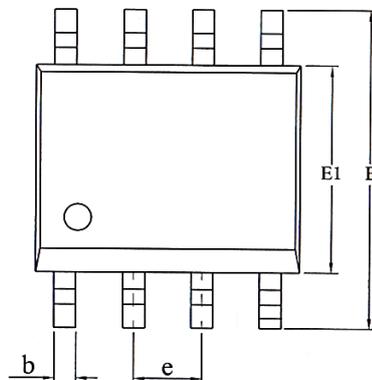
TYPICAL APPLICATION

Fig 6 Typical application of the SIT1021GQ

Note: To obtain a slower bus waveform slope, it is recommended to use a R_L/C_L combination of $660\Omega/6.8nF$, where R_L/C_L is the equivalent value of all nodes summarized. R_4 ($10k\Omega\sim 100k\Omega$) is the drop-down resistance from INH to GND. Whether to add the pull-down resistance and its value should be selected according to the status of the EN pin of the external power supply chip.

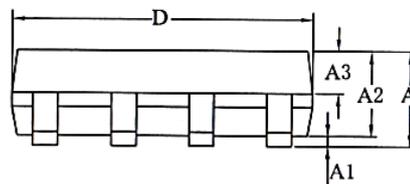
TIMING TEST CIRCUIT

Fig 7 Timing test circuit for LIN transceiver

SOP8 DIMENSIONS
PACKAGE SIZE

SYMBOL	MIN./mm	TYP./mm	MAX./mm
A	1.40	-	1.80
A1	0.10	-	0.25
A2	1.30	1.40	1.50
A3	0.60	0.65	0.70
b	0.38	-	0.51
D	4.80	4.90	5.00
E	5.80	6.00	6.20
E1	3.80	3.90	4.00
e	1.27BSC		
h	0.25	-	0.50
L	0.40	0.60	0.80
L1	1.05REF		
c	0.20	-	0.25
θ	0°	-	8°

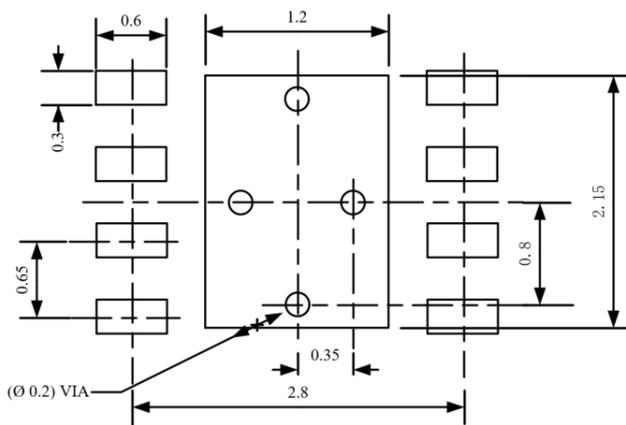
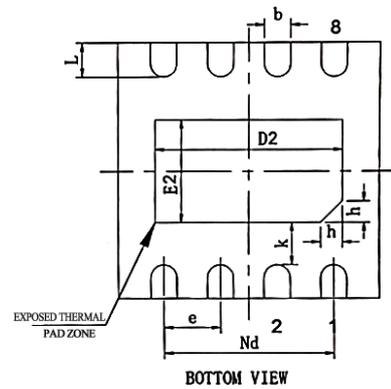
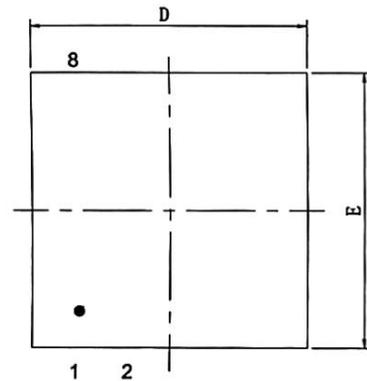


LAND PATTERN EXAMPLE (Unit: mm)

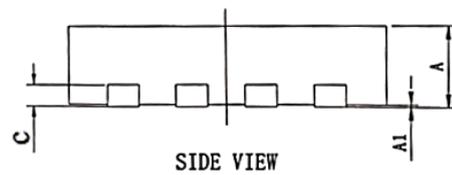


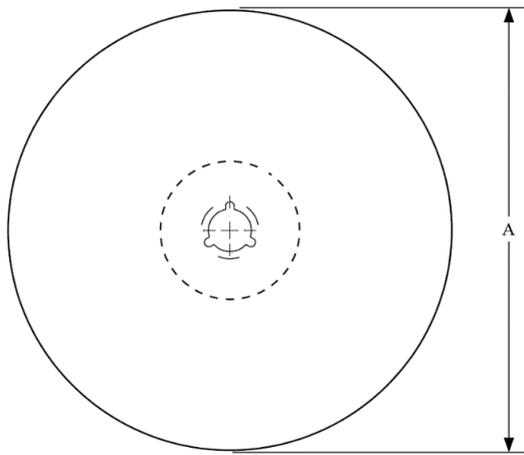
DFN3*3-8 DIMENSIONS
PACKAGE SIZE

SYMBOL	MIN./mm	TYP./mm	MAX./mm
A	0.70	0.75	0.80
A1	0	0.02	0.05
c	0.203 REF		
D	2.90	3.00	3.10
E	2.90	3.00	3.10
D2	2.05	2.15	2.25
Nd	1.95BSC		
E2	1.10	1.20	1.30
b	0.25	0.30	0.35
e	0.65 TYP		
k	0.50REF		
L	0.35	0.4	0.45
h	0.20	0.25	0.30

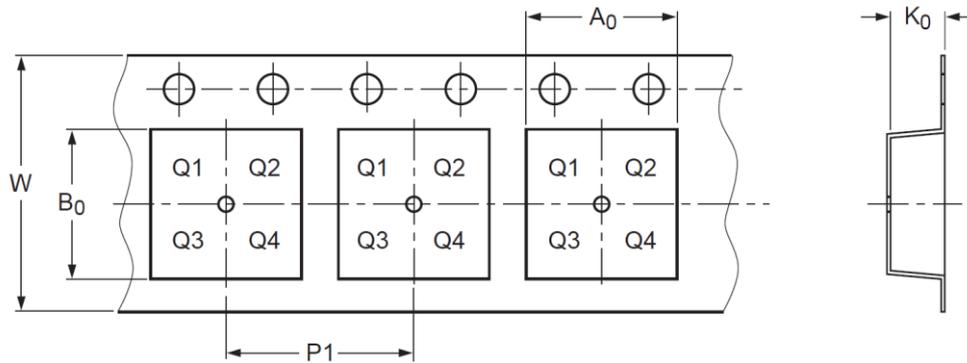
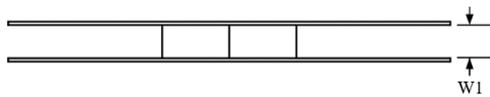


LAND PATTERN EXAMPLE (Unit: mm)



TAPE AND REEL INFORMATION


A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers



Direction of Feed →

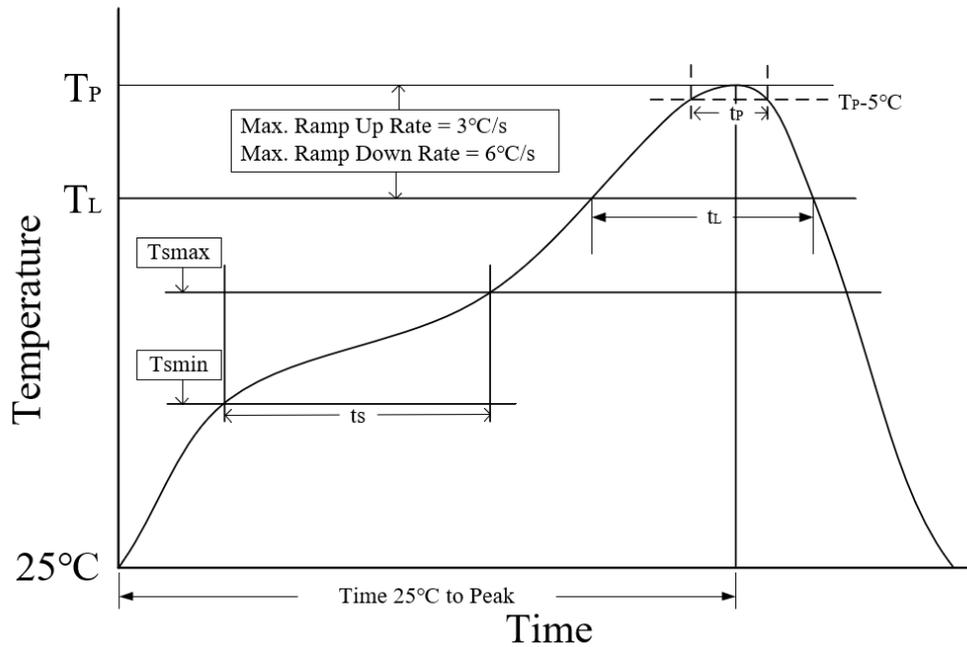
PIN1 is in quadrant 1

Package type	Reel diameter A (mm)	Tape width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)
SOP8	330±1	12.4	6.60±0.1	5.30±0.10	1.90±0.1	8.00±0.1	12.00±0.1
DFN3*3-8	329±1	12.4	3.30±0.1	3.30±0.1	1.10±0.1	8.00±0.1	12.00±0.3

ORDERING INFORMATION

TYPE NUMBER	PACKAGE	MSL	PACKING
SIT1021GQT	SOP8	MSL3	Tape and reel
SIT1021GQTK	DFN3*3-8, Small outline package, no leads	MSL1	Tape and reel

SOP8 is packed with 2500 pieces/disc in braided packaging. Leadless DFN3*3-8 is packed with 6000 pieces/disc in braided packaging.

REFLOW SOLDERING


Parameter	Lead-free soldering conditions
Ave ramp up rate (T_L to T_P)	3 °C/second max
Preheat time t_s ($T_{smin}=150\text{ °C}$ to $T_{smax}=200\text{ °C}$)	60-120 seconds
Melting time t_L ($T_L=217\text{ °C}$)	60-150 seconds
Peak temp T_P	260-265 °C
5°C below peak temperature t_p	30 seconds
Ave cooling rate (T_P to T_L)	6 °C/second max
Normal temperature 25°C to peak temperature T_P time	8 minutes max

Important statement

SIT reserves the right to change the above-mentioned information without prior notice.

REVISION HISTORY

Version number	Datasheet status	Revision Date
V1.0	Initial version.	September 2025
V1.1	Added "AEC-Q100 qualified".	December 2025